

Notice of References Cited	Application/Control No. 10/529,507	Applicant(s)/Patent Under Reexamination DAVIS ET AL.	
	Examiner David W. Scheuermann	Art Unit 2834	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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	N	JP 06086576 A	03-1994	Japan	WATANABE et al.	
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NON-PATENT DOCUMENTS

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